S/N Unknown

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Serial No.:

Filed:

Title:

Wing-Cheong Gilbert Lai et al.

Unknown

Herewith

SMALL GRAIN SIZE, CONFORMAL ALUMINUM INTERCONNECTS AND METHOD FOR THEIR FORMATION

Examiner: Unknown

Group Art Unit: Unknown

Docket: 303.261US3

PATEN

INFORMATION DISCLOSURE STATEMENT

Box Patent Application Commissioner for Patents Washington, D.C. 20231

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 et. seq., the enclosed materials are brought to the attention of the Examiner for review in connection with the above-identified patent application. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner be returned to the Applicants.

In accordance with 37 C.F.R. §1.98(d), copies of the listed documents are not provided as these references were previously cited by or submitted to the U.S. Patent Office in connection with Applicants' prior U.S. application, Serial No. 09/146,509, filed on September 3, 1998, which is relied upon for an earlier filing date under 35 U.S.C. §120.

Applicants respectfully request consideration of these references during prosecution of the above-identified matter. The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

WING-CHEONG GILBERT LAI ET AL.

By their Representatives,

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Date of Deposit: February 13, 2001

This paper or fee is being deposited on the date indicated above with the United States Postal Service pursuant to 37 CFR 1.10, and is addressed to The Commissioner for Patents, Box Patent Application, Washington, D.C. 20231.

Sheet 1 of 1 Serial No. Unknown Form 1449* Atty. Docket No.: 303.261US3 09 Applicant: Wing-Cheong Gilbert Lai et al. INFORMATION DISCLOSURE STATEMENT BY APPLICANT Filing Date: Herewith Group: Unknown (Use several sheets if necessary) U.S. PATENT DOCUMENTS **Examinar Class Subclass If Appropriata Data Name Document Number Initial 12/04/89 TU 529 Lowrey, T.A., et al. 420 4,999,160 03/12/1991 09/05/91 427 255.1 03/09/1993 Sandhu, G.S. 5,192,589 04/14/93 192 Sandhu, G.S., et al. 437 5,246,881 09/21/1993 06/17/92 Mikoshiba, N., et al. 437 187 5,316,972 05/31/1994 06/23/92 Mikoshiba, N., et al. 437 187 5,328,873 07/12/1994 12/28/92 118 726 Asaba, T., et al. 01/24/1995 5,383,970 10/01/93 01/24/1995 Doan, T.T., et al. 437 190 5,384,284 02/04/94 Fiordalice, R.W., et al.437 192 05/30/1995 5,420,072 09/01/94 531 Sandu, G.S. 01/02/1996 5,480,684 12/21/93 Kondoh, E., et al. 427 248.1 5,552,181 09/03/1996 Matsumoto, R., et al. 438 643 06/22/95 5,654,235 08/05/1997 McTeer, A. 02/05/96 437 192 5,700,718 12/23/1997 438 702 06/27/96 Givens, J.H. 03/10/1998 5,726,100 02/18/97 Sandhu, G.S., et al. 257 774 12/01/1998 5,844,318 08/22/97 257 751 12/08/1998 Trivedi, J.D., et al. 5,847,463 10/27/97 738 Roberts, C., et al. 438 5,861,344 01/19/1999 12/13/96 255.1 Vaartstra, B.A., et al. 427 5,866,205 02/02/1999 FOREIGN PATENT DOCUMENTS Translation Subclass Class Country Document Numbar Data Initial OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **Examinar Initial "Orientation Control of Chemical Vapor Deposition Fiordalice, R.W., et al., TiN Film for Barrier Applications", Journal of the Electrochemical Society, pgs. 2059-2063, (June 1996) <u>143 (6)</u>, "Study of Diffusion Barrier Perfomance in MOCVD TiN by Lee, H., et al., Transmission Electron Microscopy", Materials Research Society Symposium pgs. 205-209, (1995) Proceedings, 391, "Effect of Underlayer on Sputtered Aluminum Grain Pramanik, D., et al.,

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^{**}EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.